# Notice of References Cited Application/Control No. 10/603,410 Examiner Bernard E Souw Applicant(s)/Patent Under Reexamination LIU, ANSHENG Page 1 of 2

# **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	Α	US-6,600,842	07-2003	Yamada, Koji	385/2
*	В	US-2002/0071621 A1	06-2002	Yamada, Koji	385/2
8	С	US-4,093,345	06-1978	Logan et al.	385/2
6	D	US-5,007,062	04-1991	Chesnoy, Jose	372/26
8	Е	US-5,388,106	02-1995	Tabuchi, Haruhiko	372/20
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

# **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P.					
	Ø					
	R					
	s					
	Т					

# **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
×	υ	Tang et al., Electr. Lett. 31 (6), 1995, 451-452			
4	٧	Zhao et al., Electr. Lett. 32 (18), 1996, 1667-1668			
#	V	Cutolo et al., J. Lightwave Technol. 15 (3), 1997, 505-518			
7	х	Dainesi et al., IEEE Photonics Technol. Lett. 12 (6), 2000, 660-662			

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

### Applicant(s)/Patent Under Reexamination Application/Control No. 10/603,410 LIU, ANSHENG Notice of References Cited Art Unit Examiner Page 2 of 2 2881 Bernard E Souw **U.S. PATENT DOCUMENTS**

*	-	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
	В	US-			
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

# FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

# **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
B	U	Nowak et al., Proc. 1994 IEEE Internat. SOI Conf., 94CH35722, pp. 42-43			
	٧				
	w				
	Х				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.